ON Semiconductor®

FQA11N90C-F109

N-Channel QFET® MOSFET

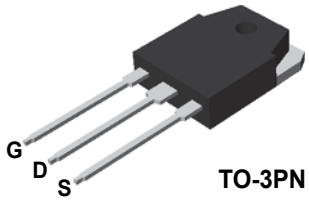
900 V, 11.0 A, 1.1 Ω

Features

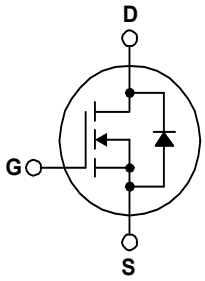
- 11 A, 900 V, $R_{DS(on)}$ = 1.1 Ω (Max.) @ V_{GS} = 10 V, I_D = 5.5 A
- Low Gate Charge (Typ. 60 nC)
- Low Crss (Typ. 23 pF)
- 100% Avalanche Tested
- RoHS compliant

Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and elec-tronic lamp ballasts.



TO-3PN



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQA11N90C_F109	Unit
V_{DSS}	Drain to Source Voltage		900	V
I_D	Drain Current	- Continuous (T_C = 25°C)	11.0	A
		- Continuous (T_C = 100°C)	6.9	A
I_{DM}	Drain Current	- Pulsed (Note 1)	44.0	A
V_{GSS}	Gate to Source Voltage		± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	960	mJ
I_{AR}	Avalanche Current	(Note 1)	11.0	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	30	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.0	V/ns
P_D	Power Dissipation	(T_C = 25°C)	300	W
		- Derate Above 25°C	2.38	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T_L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQA11N90C_F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	0.42	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	40	°C/W

September-2017, Rev. 3

Publication Order Number:
FQA11N90C-F109/D

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA11N90C-F109	FQA11N90C	TO-3PN	Tube	N/A	N/A	30 units

Electrical Characteristics T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 μA	900	--	--	V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C	--	1.02	--	V/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 900 V, V_{GS} = 0 V	--	--	10	μA
		V_{DS} = 720 V, T_C = 125°C	--	--	100	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 30 V, V_{DS} = 0 V	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 μA	3.0	--	5.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 5.5 A	--	0.91	1.1	Ω
g_{FS}	Forward Transconductance	V_{DS} = 50 V, I_D = 5.5 A	--	9.0	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	--	2530	3290	pF
C_{oss}	Output Capacitance		--	215	280	pF
C_{rss}	Reverse Transfer Capacitance		--	23	30	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 450 V, I_D = 11.0 A, R_G = 25 Ω (Note 4)	--	60	130	ns
t_r	Turn-On Rise Time		--	130	270	ns
$t_{d(off)}$	Turn-Off Delay Time		--	130	270	ns
t_f	Turn-Off Fall Time		--	85	180	ns
Q_g	Total Gate Charge	V_{DS} = 720 V, I_D = 11.0 A, V_{GS} = 10 V (Note 4)	--	60	80	nC
Q_{gs}	Gate-Source Charge		--	13	--	nC
Q_{gd}	Gate-Drain Charge		--	25	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	11.0	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	44.0	A
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 11.0 A	--	--	1.4	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0 V, I_S = 11.0 A, dI_F / dt = 100 A/μs	--	1000	--	ns
Q_{rr}	Reverse Recovery Charge		--	17.0	--	μC

Notes :

1. Repetitive rating : pulse width limited by maximum junction temperature.
2. L = 15 mH, I_{AS} = 11.0 A, V_{DD} = 50 V, R_G = 25 Ω, starting T_J = 25°C.
3. I_{SD} ≤ 11.0 A, di/dt ≤ 200 A/μs, V_{DD} ≤ BV_{DSS}, starting T_J = 25°C.
4. Essentially independent of operating temperature.

Typical Characteristics

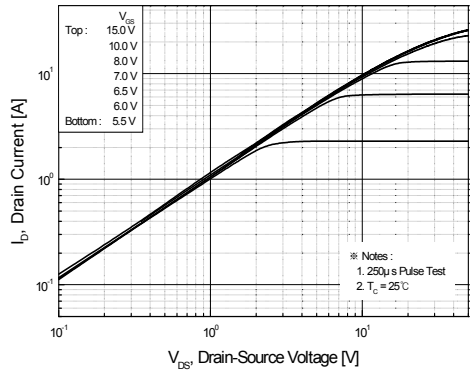


Figure 1. On-Region Characteristics

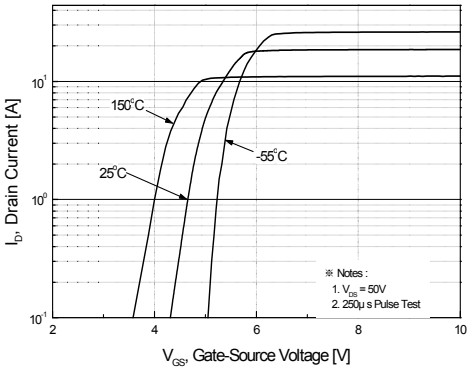


Figure 2. Transfer Characteristics

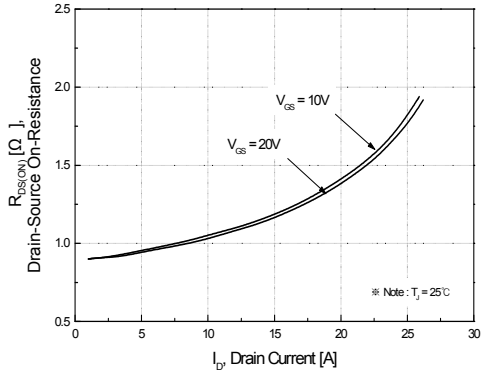


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

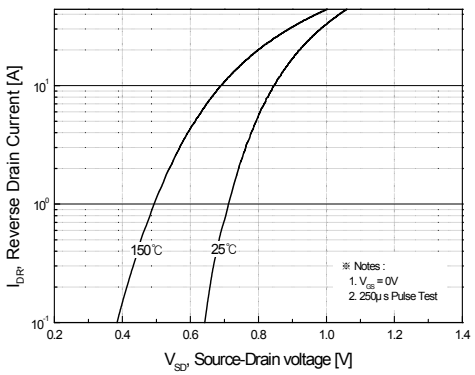


Figure 4. Body Diode Forward Voltage Variation with Source Current

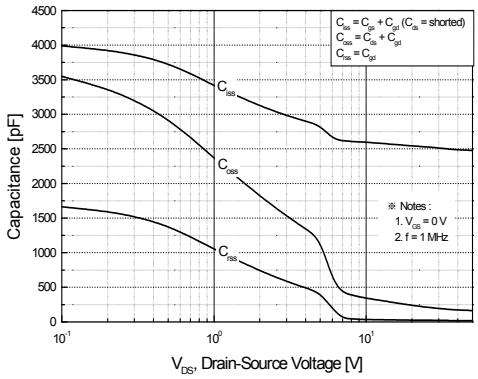


Figure 5. Capacitance Characteristics

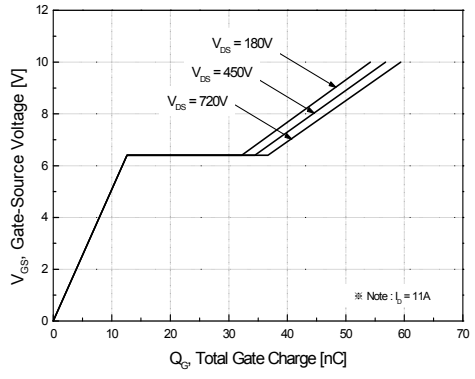


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

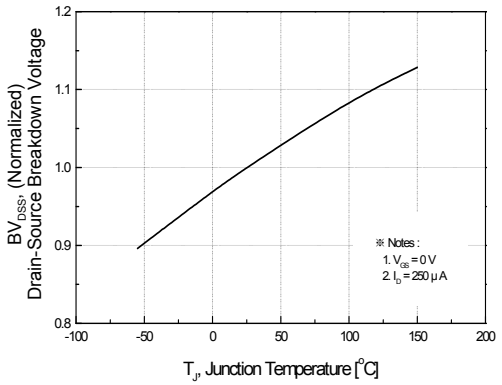


Figure 7. Breakdown Voltage Variation

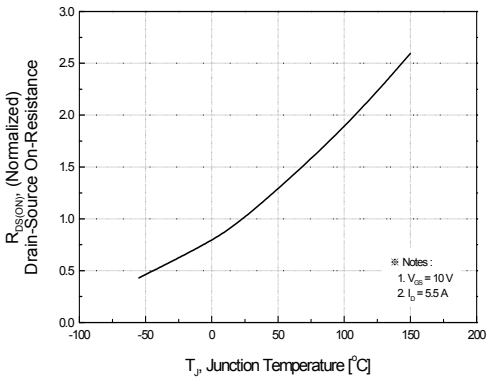


Figure 8. On-Resistance Variation

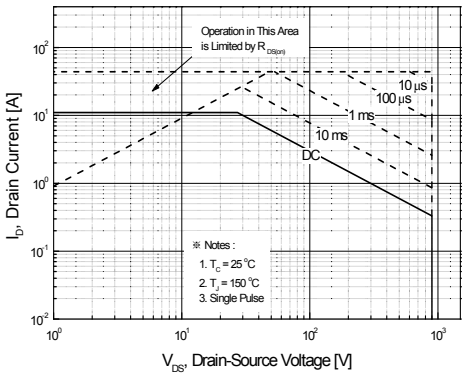


Figure 9. Maximum Safe Operating Area

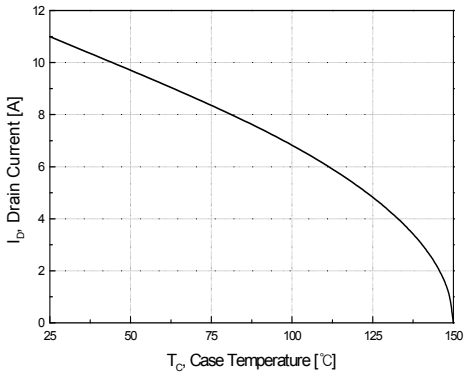


Figure 10. Maximum Drain Current vs Case Temperature

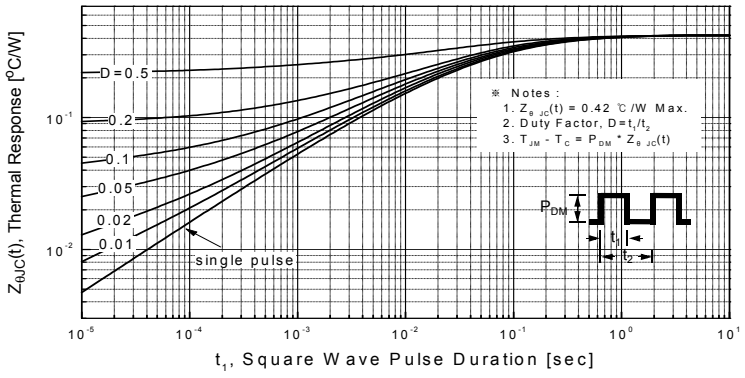


Figure 11. Transient Thermal Response Curve

Figure 12. Gate Charge Test Circuit & Waveform

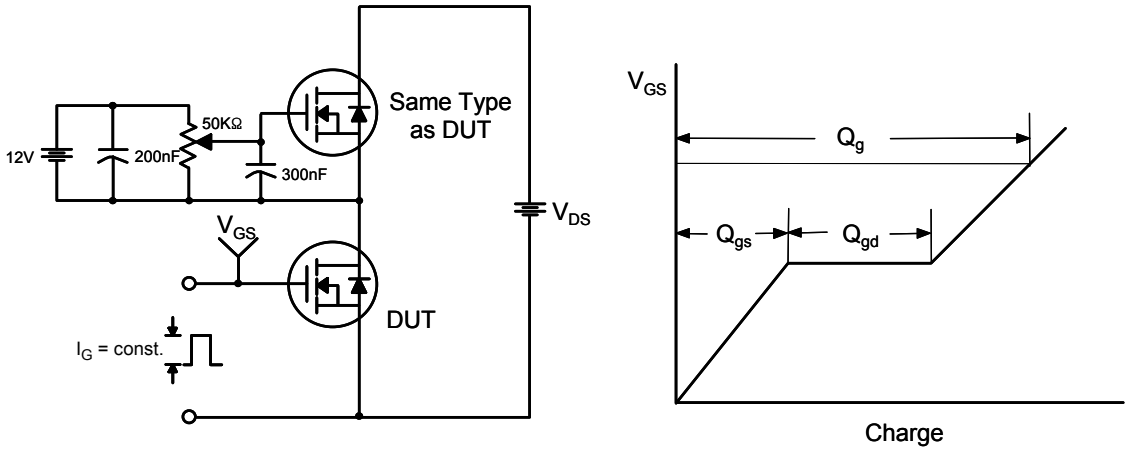


Figure 13. Resistive Switching Test Circuit & Waveforms

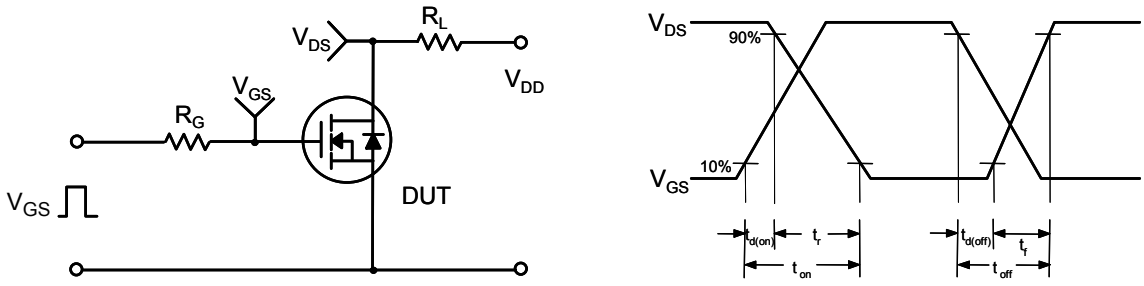


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

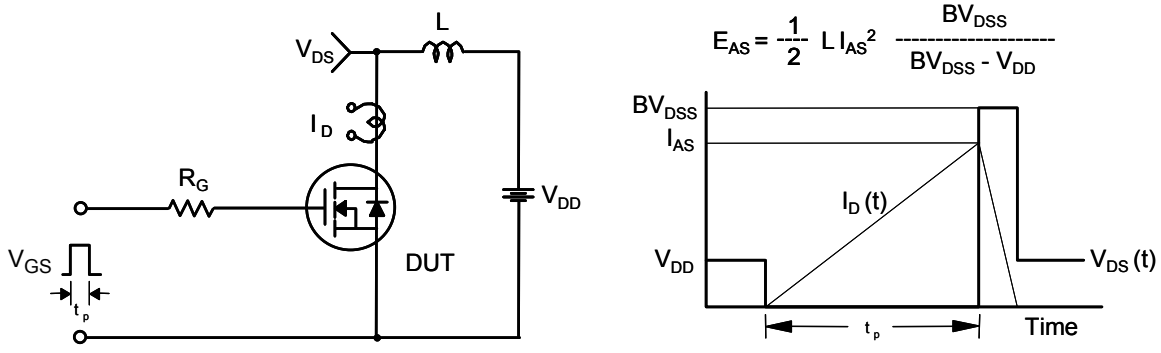
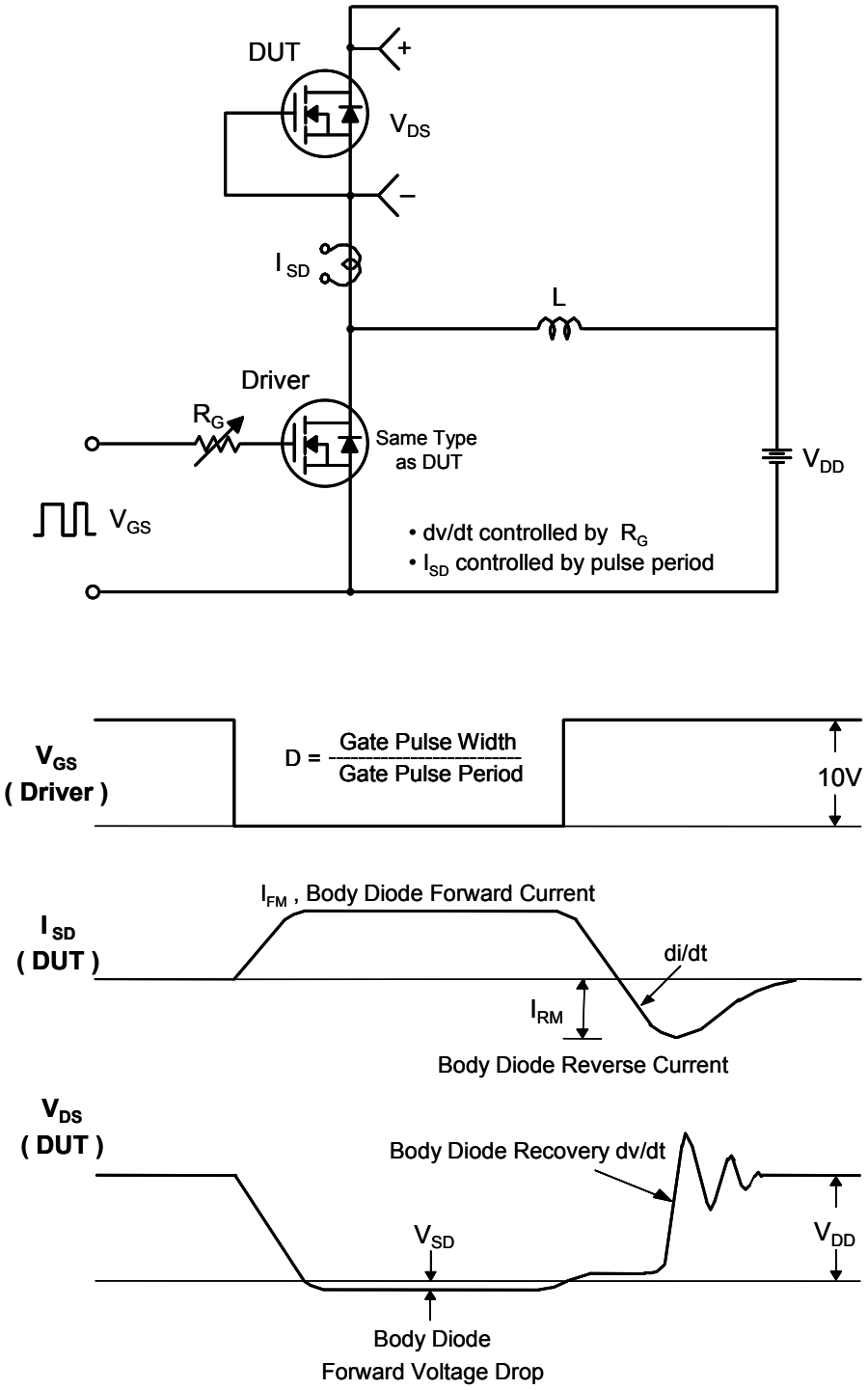


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

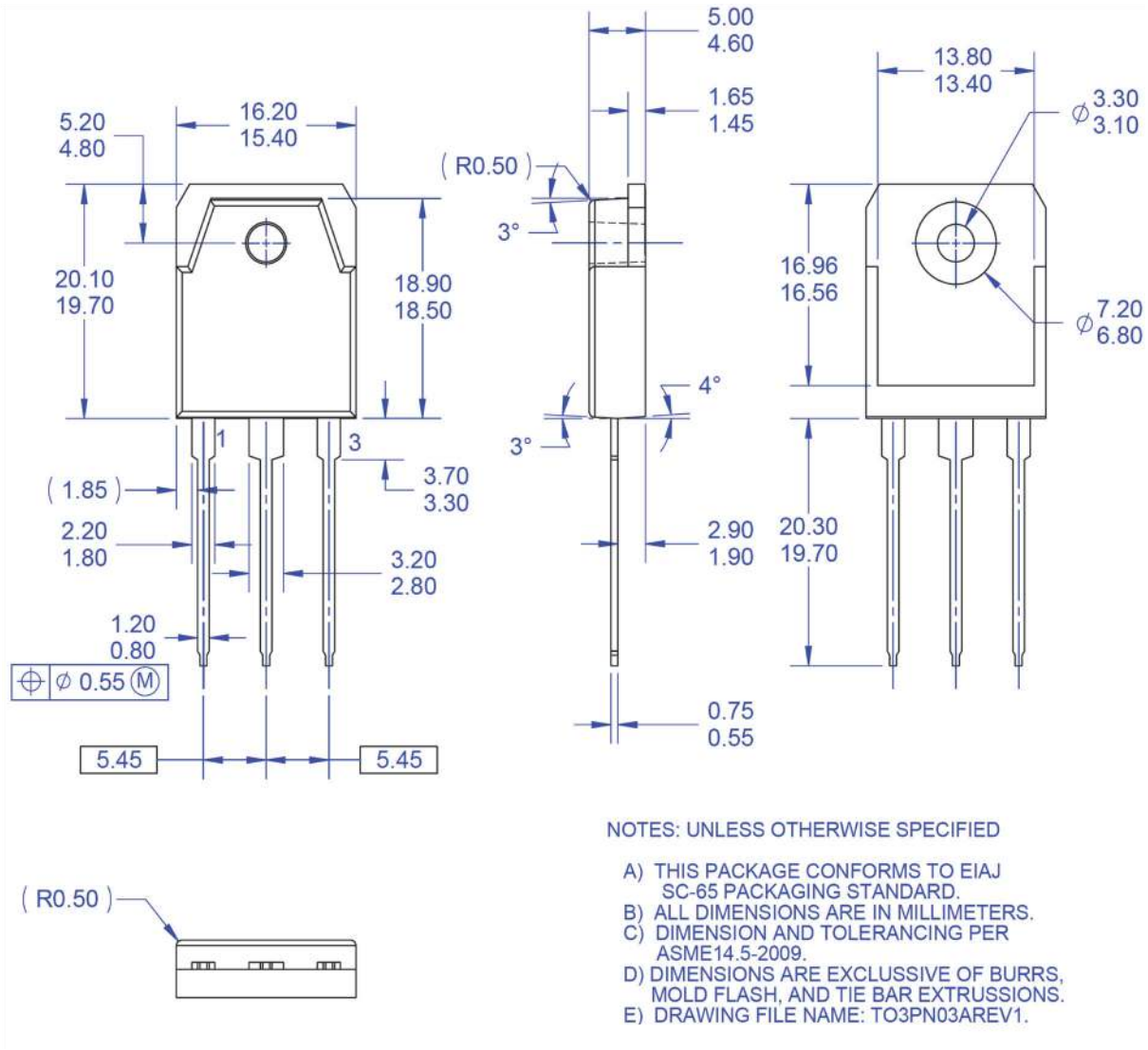


Figure 16. TO3PN, 3-Lead, Plastic, EIAJ SC-65

PUBLICATION ORDERING INFORMATION

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